## Search Notes



Application/	Control	No
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10790711

Applicant(s)/Patent Under Reexamination

**FUJINAWA ET AL.** 

Examiner

**Art Unit** 

Kaplan, Benjamin A

2109

## SEARCHED

Class	Subclass	Date	Examiner
380	45,281		
713	193		
726	27,30		

## **SEARCH NOTES**

Search Notes		Date	Examiner
	-		

## **INTERFERENCE SEARCH**

Class	Subclass	Date	Examiner

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